Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/520,823	TANAKA ET AL.
Examiner	Art Unit
Cam N. Nguyen	1754

SEARCHED						
CI	ass	Subclass	Da	ate	Exam	iner
50	D	302 303 304	10/2	105	CA,	
		324				
		327				
		349				
		415				
		439				
		525				
	7	527.1				
58	2	527.1	31	12/05	Ca	M

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
West	10/21/05	Can		
Inventor names Dearched	10/21/09	Can		